## $2.5 \mathrm{~V} / 3.3 \mathrm{~V} / 5.0 \mathrm{~V}$ 1:4 Clock Fanout Buffer

## NB3L553

## Description

The NB3L553 is a low skew 1-to 4 clock fanout buffer, designed for clock distribution in mind. The NB3L553 specifically guarantees low output-to-output skew. Optimal design, layout and processing minimize skew within a device and from device to device.

## Features

- Input/Output Clock Frequency up to 200 MHz
- Low Skew Outputs ( 35 ps ), Typical
- RMS Phase Jitter ( 12 kHz - 20 MHz ): 29 fs (Typical)
- Output goes to Three-State Mode via OE
- Operating Range: $\mathrm{V}_{\mathrm{DD}}=2.375 \mathrm{~V}$ to 5.25 V
- 5 V Tolerant Input Clock ICLK
- Ideal for Networking Clocks
- Packaged in 8-pin SOIC
- Industrial Temperature Range
- These are $\mathrm{Pb}-$ Free Devices


Figure 1. Block Diagram

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## MARKING DIAGRAMS*


DFN8
MN SUFFIX
CASE 506AA


6P = Specific Device Code
M = Date Code
= Pb-Free Package
(Note: Microdot may be in either location)
*For additional marking information, refer to Application Note AND8002/D.

PINOUT DIAGRAM


ORDERING INFORMATION

| Device | Package | Shipping $^{\dagger}$ |
| :--- | :---: | :---: |
| NB3L553DG | SOIC-8 <br> (Pb-Free) | 98 Units/Rail |
| NB3L553DR2G | SOIC-8 <br> (Pb-Free) | 2500/Tape \& Reel |
| NB3L553MNR4G | DFN-8 <br> (Pb-Free) | 1000/Tape \& Reel |

$\dagger$ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

## NB3L553

Table 1. OE, OUTPUT ENABLE FUNCTION

| $\mathbf{O E}$ | Function |
| :---: | :---: |
| 0 | Disable |
| 1 | Enable |

Table 2. PIN DESCRIPTION

| Pin \# | Name | Type | Description |
| :---: | :---: | :---: | :--- |
| 1 | V $_{\text {DD }}$ | Power | Positive supply voltage (2.375 V to 5.25 V ) |
| 2 | Q0 | (LV)CMOS/(LV)TTL Output | Clock Output 0 |
| 3 | Q1 | (LV)CMOS/(LV)TTL Output | Clock Output 1 |
| 4 | GND | Power | Negative supply voltage; Connect to ground, 0 V |
| 5 | I $_{\text {CLK }}$ | (LV)CMOS Input | Clock Input. 5.0 V tolerant |
| 6 | Q2 | (LV)CMOS/(LV)TTL Output | Clock Output 2 |
| 7 | Q3 | (LV)CMOS/(LV)TTL Output | Clock Output 3 |
| 8 | OE | (LV)TTL Input | V <br> condition default. Use from 1 to 10 kOhms external resistor to force an open con- <br> dition default state. |
| - | EP | Thermal Exposed Pad | (DFN8 only) Thermal exposed pad must be connected to a sufficient thermal <br> conduit. Electrically connect to the most negative supply (GND) or leave uncon- <br> nected, floating open. |

## NB3L553

Table 3. MAXIMUM RATINGS

| Symbol | Parameter | Condition 1 | Condition 2 | Rating | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{DD}}$ | Positive Power Supply | GND $=0 \mathrm{~V}$ | - | 6.0 | V |
| $\mathrm{~V}_{\mathrm{I}}$ | Input Voltage | OE <br> $\mathrm{I}_{\mathrm{CLK}}$ | $\mathrm{GND}=0 \mathrm{~V}$ and <br> $\mathrm{V}_{\mathrm{DD}}=2.375 \mathrm{~V}$ to 5.25 V | GND $-0.5 \leq \mathrm{V}_{1} \leq \mathrm{V}_{\mathrm{DD}}+0.5$ <br> $\mathrm{GNDD}-0.5 \leq \mathrm{V}_{1} \leq 5.75$ | V |
| $\mathrm{~T}_{\mathrm{A}}$ | Operating Temperature Range, <br> Industrial | - | - | $\geq-40$ to $\leq+85$ | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ | Storage Temperature Range | - | - | -65 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\theta_{\mathrm{JA}}$ | Thermal Resistance <br> (Junction-to-Ambient) | 0 Ifpm <br> 500 Ifpm | SOIC-8 | 190 | 130 |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. JEDEC standard multilayer board - 2S2P (2 signal, 2 power)

Table 4. ATTRIBUTES

| Characteristic | Value |
| :---: | :---: |
| Human Body Model <br> Machine Model | $\begin{gathered} \hline>2 \mathrm{kV} \\ >150 \mathrm{~V} \\ >2 \mathrm{kV} \end{gathered}$ |
| Moisture Sensitivity, Indefinite Time Out of Drypack (Note 2) | Level 1 |
| Flammability Rating Oxygen Index: 28 to 34 | UL-94 code V-0 @ 0.125 in |
| Transistor Count | 531 Devices |
| Meets or Exceeds JEDEC Standard EIA/JESD78 IC Latchup Test |  |

2. For additional Moisture Sensitivity information, refer to Application Note AND8003/D.

Table 5. DC CHARACTERISTICS $\left(\mathrm{V}_{\mathrm{DD}}=2.375 \mathrm{~V}\right.$ to $2.625 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)$ (Note 3)

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| IDD | Power Supply Current @ 135 MHz , No Load | - | 25 | 30 | mA |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage - $\mathrm{I}_{\mathrm{OH}}=-16 \mathrm{~mA}$ | 1.7 | - | - | V |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage - $\mathrm{IOL}=16 \mathrm{~mA}$ | - | - | 0.4 | V |
| $\mathrm{V}_{\mathrm{IH},}$ I $\mathrm{I}_{\text {LKK }}$ | Input HIGH Voltage, ICLK | $\left(\mathrm{V}_{\mathrm{DD}} \div 2\right)+0.5$ | - | 5.0 | V |
| $\mathrm{V}_{\text {IL, }}$ I CLK | Input LOW Voltage, ICLK | - | - | $\left(V_{D D} \div 2\right)-0.5$ | V |
| $\mathrm{V}_{\mathrm{IH},} \mathrm{OE}$ | Input HIGH Voltage, OE | 1.8 | - | $\mathrm{V}_{\mathrm{DD}}$ | V |
| $\mathrm{V}_{\text {IL, }} \mathrm{OE}$ | Input LOW Voltage, OE | - | - | 0.7 | V |
| ZO | Nominal Output Impedance | - | 20 | - | $\Omega$ |
| CIN | Input Capacitance, ICLK, OE | - | 5.0 | - | pF |
| IOS | Short Circuit Current | - | $\pm 28$ | - | mA |

DC CHARACTERISTICS $\left(\mathrm{V}_{\mathrm{DD}}=3.15 \mathrm{~V}\right.$ to $3.45 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)$ (Note 3 )

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| IDD | Power Supply Current @ 135 MHz , No Load | - | 35 | 40 | mA |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage $-\mathrm{I}_{\mathrm{OH}}=-25 \mathrm{~mA}$ | 2.4 | - | - | V |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage - $\mathrm{I}_{\text {OL }}=25 \mathrm{~mA}$ | - | - | 0.4 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage - $\mathrm{I}_{\mathrm{OH}}=-12 \mathrm{~mA}$ (CMOS level) | $\mathrm{V}_{\mathrm{DD}}-0.4$ | - | - | V |
| $\mathrm{V}_{\mathrm{IH}}$, ICLK | Input HIGH Voltage, ICLK | $\left(V_{D D} \div 2\right)+0.7$ | - | 5.0 | V |
| $\mathrm{V}_{\mathrm{IL},}$ I CLK | Input LOW Voltage, ICLK | - | - | $\left(V_{D D} \div 2\right)-0.7$ | V |
| $\mathrm{V}_{\text {IH, }}$ OE | Input HIGH Voltage, OE | 2.0 | - | $V_{\text {DD }}$ | V |
| $\mathrm{V}_{\text {IL, }}$ OE | Input LOW Voltage, OE | 0 | - | 0.8 | V |
| ZO | Nominal Output Impedance | - | 20 | - | $\Omega$ |
| CIN | Input Capacitance, OE | - | 5.0 | - | pF |
| IOS | Short Circuit Current | - | $\pm 50$ | - | mA |

DC CHARACTERISTICS $\left(\mathrm{V}_{\mathrm{DD}}=4.75 \mathrm{~V}\right.$ to $5.25 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)$ (Note 3)

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| IDD | Power Supply Current @ 135 MHz , - No Load | - | 45 | 85 | mA |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage - $\mathrm{IOH}^{\text {a }}=-35 \mathrm{~mA}$ | 2.4 | - | - | V |
| $\mathrm{V}_{\text {OL }}$ | Output LOW Voltage - $\mathrm{IOL}=35 \mathrm{~mA}$ | - | - | 0.4 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage - $\mathrm{I}_{\mathrm{OH}}=-12 \mathrm{~mA}$ (CMOS level) | $\mathrm{V}_{\mathrm{DD}}-0.4$ | - | - | V |
| $\mathrm{V}_{\mathrm{IH}}$, ICLK | Input HIGH Voltage, ICLK | $\left(V_{D D} \div 2\right)+1$ | - | 5.0 | V |
| $\mathrm{V}_{\text {IL, }}$ ICLK | Input LOW Voltage, ICLK | - | - | $\left(V_{D D} \div 2\right)-1$ | V |
| $\mathrm{V}_{\mathrm{IH},} \mathrm{OE}$ | Input HIGH Voltage, OE | 2.0 | - | $V_{\text {DD }}$ | V |
| $\mathrm{V}_{\text {IL, }}$ OE | Input LOW Voltage, OE | - | - | 0.8 | V |
| ZO | Nominal Output Impedance | - | 20 | - | $\Omega$ |
| CIN | Input Capacitance, OE | - | 5.0 | - | pF |
| IOS | Short Circuit Current | - | $\pm 80$ | - | mA |

NB3L553

Table 6. AC CHARACTERISTICS; $\mathrm{V}_{\mathrm{DD}}=2.5 \mathrm{~V} \pm 5 \%\left(\mathrm{~V}_{\mathrm{DD}}=2.375 \mathrm{~V}\right.$ to $2.625 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)$ (Note 3)

| Symbol | Characteristic | Min | Typ | Max | Unit |
| :---: | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{f}_{\text {in }}$ | Input Frequency | - | - | 200 | MHz |
| $\mathrm{t}_{\mathrm{r}} / \mathrm{t}_{\mathrm{f}}$ | Output rise and fall times; 0.8 V to 2.0 V | - | 1.0 | 1.5 | ns |
| $\mathrm{t}_{\mathrm{pd}}$ | Propagation Delay, CLK to $\mathrm{Q}_{\mathrm{n}}$ (Note 4) | 2.2 | 3.0 | 5.0 | ns |
| $\mathrm{t}_{\text {skew }}$ | Output-to-output skew; (Note 5) | - | 35 | 50 | ps |
| $\mathrm{t}_{\text {skew }}$ | Device-to-device skew, (Note 5) | - | - | 500 | ps |

AC CHARACTERISTICS; $\mathrm{V}_{\mathrm{DD}}=3.3 \mathrm{~V} \pm 5 \%\left(\mathrm{~V}_{\mathrm{DD}}=3.15 \mathrm{~V}\right.$ to $3.45 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)(\mathrm{Note} 3)$

| Symbol | Characteristic | Conditions | Min | Typ | Max | Unit |
| :---: | :--- | :--- | :---: | :---: | :---: | :---: |
| $\mathrm{f}_{\text {in }}$ | Input Frequency |  | - | - | 200 | MHz |
| $\mathrm{t}_{\mathrm{jitter}}(\phi)$ | RMS Phase Jitter (Integrated $12 \mathrm{kHz}-$ <br> 20 MHz (See Figures 2 and 3) | $\mathrm{f}_{\text {carrier }}=100 \mathrm{MHz}$ | - | 18 | - | fs |
| $\mathrm{t}_{\mathrm{r}} / \mathrm{t}_{\mathrm{f}}$ | Output rise and fall times; 0.8 V to 2.0 V |  | - | 0.6 | 1.0 | ns |
| $\mathrm{t}_{\text {pd }}$ | Propagation Delay, CLK to $\mathrm{Q}_{\mathrm{n}}($ Note 4) |  | 2.0 | 2.4 | 4.0 | ns |
| $\mathrm{t}_{\text {skew }}$ | Output-to-output skew; (Note 5) |  | - | 35 | 50 | ps |
| $\mathrm{t}_{\text {skew }}$ | Device-to-device skew, (Note 5) |  | - | - | 500 | ps |

AC CHARACTERISTICS; $\mathrm{V}_{\mathrm{DD}}=5.0 \mathrm{~V} \pm 5 \%\left(\mathrm{~V}\right.$ DD $=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{GND}=0 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $\left.+85^{\circ} \mathrm{C}\right)$ (Note 3)

| Symbol | Characteristic | Min | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{f}_{\text {in }}$ | Input Frequency |  | - | - | 200 | MHz |
| $\mathrm{t}_{\mathrm{j} \text { itter }}(\phi)$ | RMS Phase Jitter (Integrated 12 kHz 20 MHz ) (See Figures 2 and 3) | $\mathrm{f}_{\text {carrier }}=100 \mathrm{MHz}$ | - | 29 | - | fs |
| $\mathrm{t}_{\mathrm{r}} / \mathrm{t}_{\mathrm{f}}$ | Output rise and fall times; 0.8 V to 2.0 V |  | - | 0.3 | 0.7 | ns |
| $\mathrm{t}_{\mathrm{pd}}$ | Propagation Delay, CLK to $\mathrm{Q}_{\mathrm{n}}$ (Note 4) |  | 1.7 | 2.5 | 4.0 | ns |
| $\mathrm{t}_{\text {skew }}$ | Output-to-output skew; (Note 5) |  | - | 35 | 50 | ps |
| $\mathrm{t}_{\text {skew }}$ | Device-to-device skew, (Note 5) |  | - | - | 500 | ps |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
3. Outputs loaded with external $R_{L}=33 \Omega$ series resistor and $C_{L}=15 \mathrm{pF}$ to GND. Duty cycle out = duty in. A $0.01 \mu \mathrm{~F}$ decoupling capacitor should be connected between $V_{D D}$ and GND.
4. Measured with rail-to-rail input clock
5. Measured on rising edges at $\mathrm{V}_{\mathrm{DD}} \div 2$ between any two outputs with equal loading.


Offset Frequency from Carrier
( Hz )
Figure 2. Phase Noise Plot at 100 MHz at an Operating Voltage of 3.3 V, Room Temperature
The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz ; as shown in the shaded area) is 18 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 93.16 fs ).


Figure 3. Phase Noise Plot at 100 MHz at an Operating Voltage of 5 V , Room Temperature
The above plot captured using Agilent E5052A shows Additive Phase Noise of the NB3L553 device measured with an input source generated by Agilent E8663B. The RMS phase jitter contributed by the device (integrated between 12 kHz to 20 MHz ; as shown in the shaded area) is 29 fs (RMS Phase Jitter of the input source is 75.40 fs and Output (DUT+Source) is 103.85 fs ).


DFN8 2x2, 0.5P
CASE 506AA
ISSUE F


1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
. CONTROLLING DIMENSION: MILLIMETERS
2. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.20 MM FROM TERMINAL TIP.
. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

| DIM | MILLIMETERS |  |
| :---: | :---: | :---: |
|  | MIN | MAX |
| A | 0.80 | 1.00 |
| A1 | 0.00 | 0.05 |
| A3 | 0.20 REF |  |
| b | 0.20 | 0.30 |
| D | 2.00 BSC |  |
| D2 | 1.10 | 1.30 |
| E | 2.00 BSC |  |
| E2 | 0.70 | 0.90 |
| e | 0.50 BSC |  |
| K | 0.30 REF |  |
| L | 0.25 | 0.35 |
| L1 | --- | 0.10 |

## RECOMMENDED SOLDERING FOOTPRINT*



BOTTOM VIEW

## GENERIC

MARKING DIAGRAM*


XX = Specific Device Code
M = Date Code

- = Pb-Free Device
*This information is generic. Please refer to device data sheet for actual part marking. $\mathrm{Pb}-\mathrm{Free}$ indicator, " G " or microdot " r ", may or may not be present. Some products may not follow the Generic Marking.


DIMENSIONS: MILLIMETERS
*For additional information on our Pb -Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

| DOCUMENT NUMBER: | 98AON18658D | Electronic versions are uncontrolled except when accessed directly from the Document Repository. <br> Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red. |
| ---: | :--- | :--- | :--- |
| DESCRIPTION: | DFN8, 2.0X2.0, 0.5MM PITCH | PAGE 1 OF 1 |

[^0]

SOIC-8 NB
CASE 751-07
ISSUE AK
SCALE 1:1
NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
. CONTROLLING DIMENSION: MILLIMETER.
2. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
3. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
4. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
5. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

| DIM | MILLIMETERS |  | INCHES |  |
| :---: | :---: | :---: | :---: | :---: |
|  | MIN | MAX | MIN | MAX |
|  | 4.80 | 5.00 | 0.189 | 0.197 |
| B | 3.80 | 4.00 | 0.150 | 0.157 |
| C | 1.35 | 1.75 | 0.053 | 0.069 |
| D | 0.33 | 0.51 | 0.013 | 0.020 |
| G | 1.27 BSC |  | 0.050 BSC |  |
| H | 0.10 | 0.25 | 0.004 | 0.010 |
| J | 0.19 | 0.25 | 0.007 | 0.010 |
| K | 0.40 | 1.27 | 0.016 | 0.050 |
| M | 0 | $0^{\circ}$ | $8^{\circ}$ | 0 |
|  | $\circ$ | 8 |  |  |
| N | 0.25 | 0.50 | 0.010 | 0.020 |
| S | 5.80 | 6.20 | 0.228 | 0.244 |

GENERIC
MARKING DIAGRAM*



XXXXX = Specific Device Code
A = Assembly Location
L Wafer Lot
= Year
= Work Week
= Pb-Free Package
*This information is generic. Please refer to device data sheet for actual part marking. $\mathrm{Pb}-\mathrm{Free}$ indicator, " G " or microdot " $\mathrm{=}$ ", may or may not be present. Some products may not follow the Generic Marking.
*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## STYLES ON PAGE 2

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| ---: | :--- | :--- | :--- |
| DESCRIPTION: | SOIC-8 NB | PAGE 1 OF 2 |

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SOIC-8 NB
CASE 751-07
ISSUE AK
DATE 16 FEB 2011

STYLE

| PIN 1. | EMITTER |
| ---: | :--- |
| 2. | COLLECTOR |
| 3. | COLLECTOR |
| 4. | EMITTER |
| 5. | EMITTER |
| 6. | BASE |
| 7. | BASE |
| 8. | EMITTER |
| STYLE 5: |  |
| PIN 1. | DRAIN |
| 2. | DRAIN |
| 3. | DRAIN |
| 4. | DRAIN |
| 5. | GATE |
| 6. | GATE |
| 7. | SOURCE |
| 8. | SOURCE |

STYLE 9:
PIN 1. EMITTER, COMMON
COLLECTOR, DIE \#1 COLLECTOR, DIE \#2 EMITTER, COMMON EMITTER, COMMON BASE, DIE \#2
BASE, DIE \#1
8. EMITTER, COMMON

STYLE 13:
PIN 1. N.C.
2. SOURCE
3. SOURCE

GATE
DRAIN
DRAIN
DRAIN
8. DRAIN

STYLE 17:
PIN 1. VCC
V2OUT
V10UT
V10UT
TXE
RXE
VEE
8. ACC

STYLE 21:
PIN 1. CATHODE 1
2. CATHODE 2
3. CATHODE 3

CATHODE 4
CATHODE 5
6. COMMON ANODE
7. COMMON ANODE
8. CATHODE 6

STYLE 25:
PIN 1. VIN
2. $N / C$

REXT
GND
IOUT
IOUT
IOUT
8. IOUT

## STYLE 29:

PIN 1. BASE, DIE \#
EMITTER, \#1
BASE, \#2
. EMITTER, \#2
5. COLLECTOR, \#2
6. COLLECTOR, \#2
7. COLLECTOR, \#1
7. COLLECTOR, \#1

STYLE
PIN 1. COLIECTOR, DIE,
2. COLLECTOR, \#1
3. COLLECTOR, \#2

COLLECTOR, \#2
BASE, \#2
. EMITTER, \#2
7. BASE, \#1
8. EMITTER, \#1

STYLE 6:
PIN 1. SOURCE
DRAIN
3. DRAIN
4. SOURCE

SOURCE
6. GATE
7. GATE
8. SOURCE

STYLE 10:
PIN 1. GROUND
2. BIAS 1
3. OUTPUT

GROUND
GROUND
BIAS 2
7. INPUT
8. GROUND

STYLE 14:
PIN 1. N-SOURCE
2. N-GATE

P-SOURCE
P-GATE
5-DRAIN
. P-DRAIN
7. N -DRAIN
8. N-DRAIN

STYLE 18
PIN 1. ANODE
2. ANODE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. CATHODE
8. CATHODE

STYLE 22 :
PIN 1. I/O LINE
2. COMMON CATHODE/VCC
3. COMMON CATHODE/VCC
4. I/O LINE 3
5. COMMON ANODE/GND
6. I/O LINE 4
7. I/O LINE 5
8. COMMON ANODE/GND

STYLE 26:
PIN 1. GND
2. $\mathrm{dv} / \mathrm{dt}$
3. ENABLE
4. ILIMIT
5. SOURCE

SOURCE
7. SOURCE

STYLE 30:
PIN 1. DRAIN 1
2. DRAIN 1
. GATE 2
4. SOURCE 2
5. SOURCE 1/DRAIN 2
. SOURCE 1/DRAIN 2
SOURCE 1/DRAIN 2
8. GATE 1

STYLE 3
STYLE
2. DRAIN, DIE
2. DRAIN, \#1
2. DRAIN, \#
3. DRAIN, \#2
4. DRAIN, \#2
5. GATE, \#2
7. GATE, \#1
8. SOURCE, \#1

## STYLE 7

PIN 1. INPUT
2. EXTERNAL BYPASS
3. THIRD STAGE SOURCE
4. GROUND
5. DRAIN
6. GATE 3
7. SECOND STAGE Vd
8. FIRST STAGE Vd

## STYLE 11:

PIN 1. SOURCE
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. DRAIN 2
7. DRAIN
8. DRAIN 1

## STYLE 15:

PIN 1. ANODE 1
2. ANODE 1
3. ANODE 1
4. ANODE 1
5. CATHODE, COMMON
6. CATHODE, COMMON
7. CATHODE, COMMON
8. CATHODE, COMMON

## STYLE 19:

PIN 1. SOURCE
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. MIRROR 2
7. DRAIN 1
8. MIRROR 1

## STYLE 23:

PIN 1. LINE 1 IN
2. COMMON ANODE/GND
3. COMMON ANODE/GND
4. LINE 2 IN
5. LINE 2 OUT
6. COMMON ANODE/GND
7. COMMON ANODE/GND
8. LINE 1 OUT

STYLE 27:
PIN 1. ILIMIT
2. OVLO
3. UVLO
4. INPUT+
5. INPUT+
5. SOURCE
6. SOURCE
7. SOURCE
8. DRAIN

STYLE 4:
PIN 1. ANODE
2. ANODE
3. ANODE
4. ANODE
5. ANODE
6. ANODE
8. COMMON CATHODE

## STYLE 8:

PIN 1. COLLECTOR, DIE \#1
2. BASE, \#1
3. BASE, \#2
4. COLLECTOR, \#2
5. COLLECTOR, \#2
6. EMITTER, \#2
7. EMITTER, \#1
8. COLLECTOR, \#1

## STYLE 12

PIN 1. SOURCE
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

## STYLE 16:

PIN 1. EMITTER, DIE \#1
2. BASE, DIE \#1
3. EMITTER, DIE \#2
3. EMITTER, DIE
4. BASE, DIE \#2
4. BASE, DIE \#2
6. COLLECTOR, DIE \#2
7. COLLECTOR, DIE \#1
8. COLLECTOR, DIE \#1

## STYLE 20:

PIN 1. SOURCE (N)
2. GATE (N)
3. SOURCE (P)
4. GATE (P)
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

## STYLE 24:

PIN 1. BASE
2. EMITTER
3. COLLECTOR/ANODE
4. COLLECTOR/ANODE
5. CATHODE
6. CATHODE
7. COLLECTOR/ANODE
8. COLLECTOR/ANODE

## STYLE 28:

PIN 1. SW_TO_GND
2. DASIC $\bar{O} F F$
3. DASIC_SW_DET
4. GND
5. V_MON
6. VBUULK
7. VBULK
8. VIN

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| DESCRIPTION: | SOIC-8 NB | - PAGE 2 OF2 |

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